



EIGHTEENTH ANNUAL

BiTS™

Burn-in & Test Strategies Workshop

March 5 - 8, 2017

Hilton Phoenix / Mesa Hotel
Mesa, Arizona

Archive – Session 8

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Session 8

Hongjun Yao
Session Chair

BiTS Workshop 2017 Schedule

Solutions Day

Wednesday March 8 - 10:30 am

Contact Frequency

" Small Form Factor Cantilever Concepts for High Performance Analog / RF Applications"

Gerhard Gschwendtberger – Cohu

"MRC (MEMS Rubber Contact) Socket Bump Particle Structure & Performance Analysis"

BoHyun Kim, Dave Oh, Justin Yun - TSE Co., Ltd

"Flat Probe Technology For High Frequency Test"

Jason Mroczkowski, Nadia Steckler - Xcerra

MRC (MEMS Rubber Contact) Socket Bump Particle Structure & Performance Analysis

Justin Yun
Bo Hyun Kim
Dave Oh



BiTS Workshop
March 5 - 8, 2017

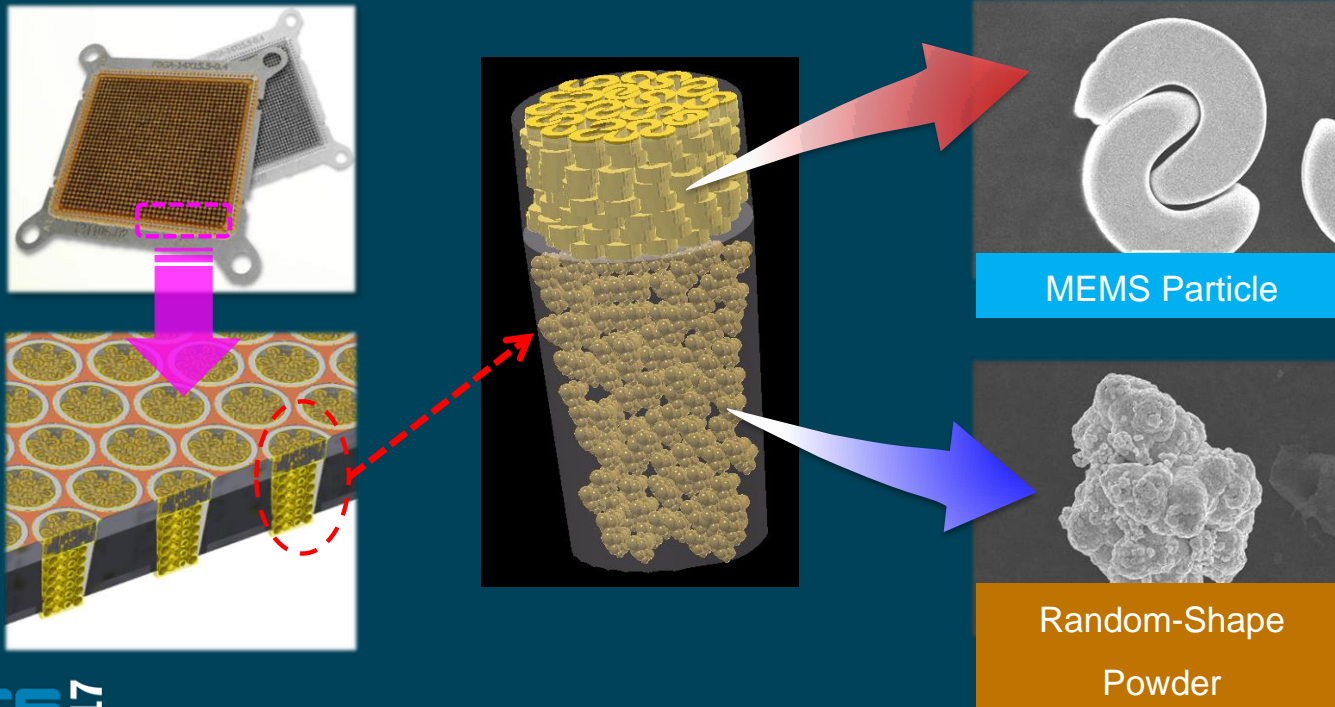


Overview

- **MRC Socket Background**
- **Investigation**
- **Lab & Production Test Results Review**
- **Analysis**
- **Summary & Conclusion**

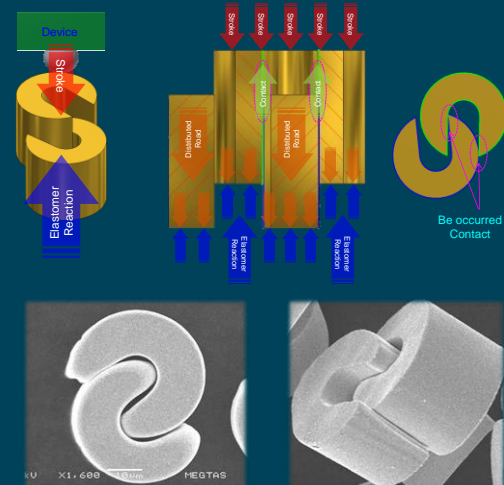
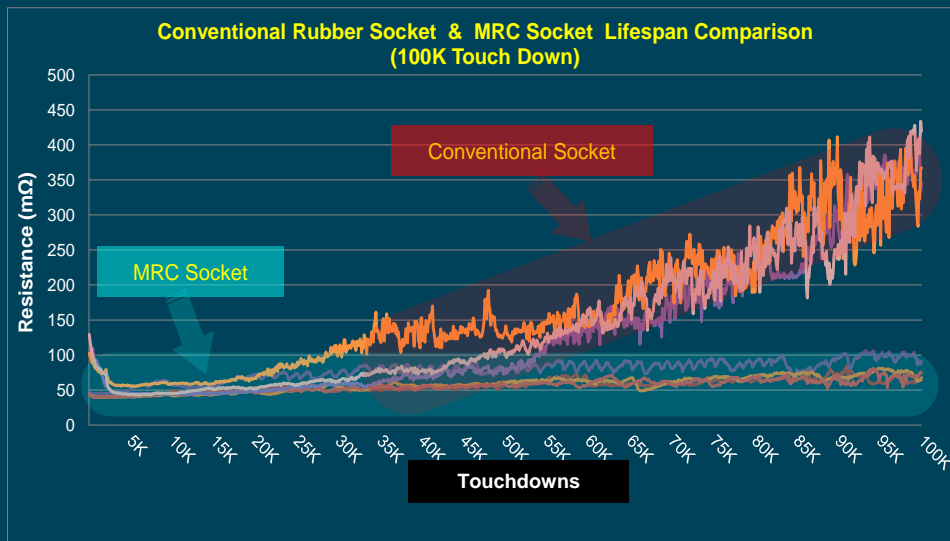
MRC Socket Background

- MEMS particle is applied to bump for good contact with balls of Package
 - ✓ Abrasion, Deflection and Tin build-up are improved



MRC Socket Background

- **MRC vs Conventional Rubber Socket Lifespan**
 - ✓ **MRC : Consistent Cres. over 100K Touchdown**

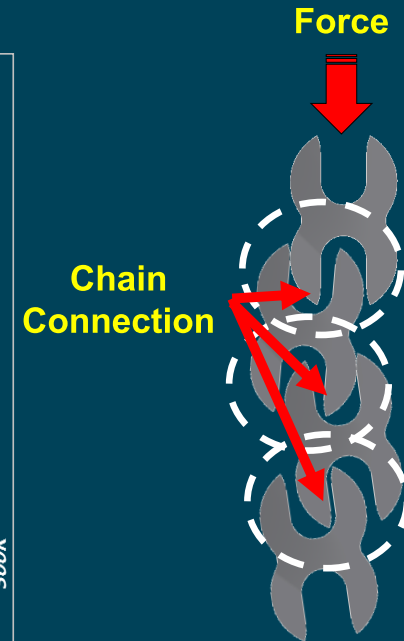
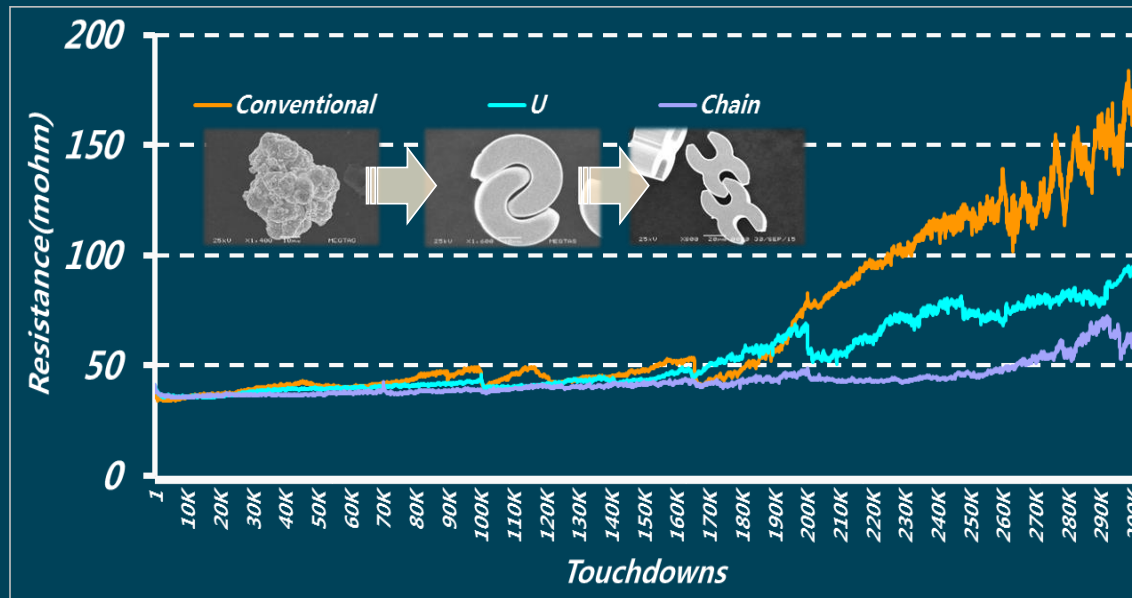


Docking!!

- **Why is MRC socket performance better than conventional rubber socket?**
 - ✓ **Contact reliability is improved by electromechanical docking of MEMS particles.**

MRC Socket Background

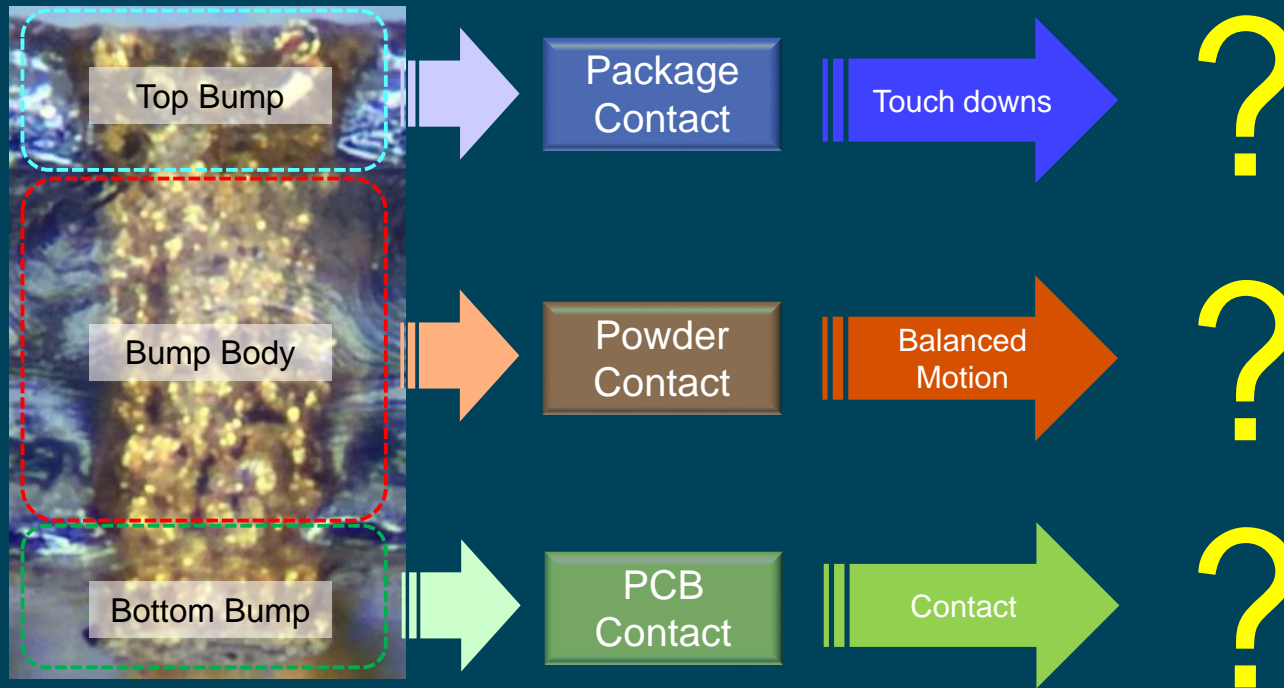
■ Docking Chain Effect of MEMS Particle



- ✓ Alternative particle shape increased contact area and improved docking
- ✓ Improvement in electrical performance (Resistance, C.C.C, Lifespan)

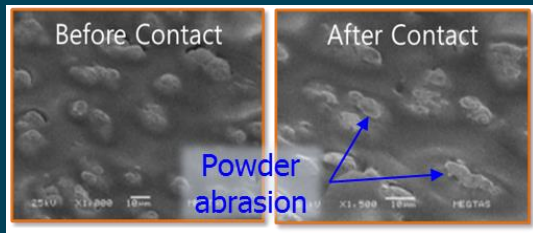
Investigation

- What kind of particle on each layer is good for durability ?
 - ✓ Each bump has 3 layers – Top, Body, Bottom

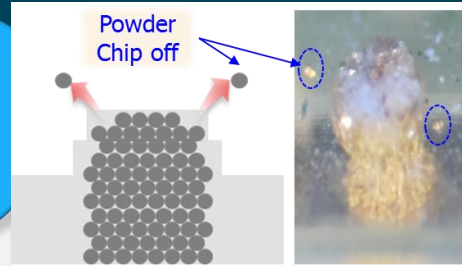


Investigation

- What is the characteristic of particle?

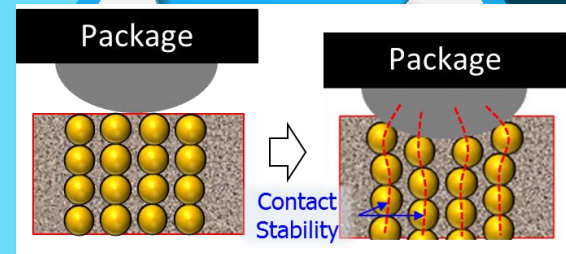


ADHESION
with
SILICONE



HARDNESS

CONSISTENT
CONTACT

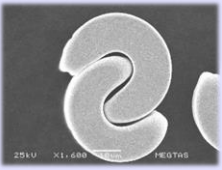
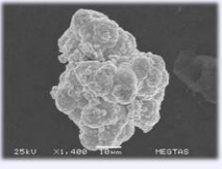
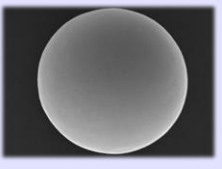


COST



Investigation

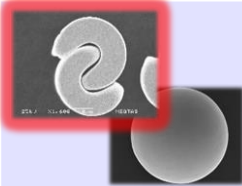
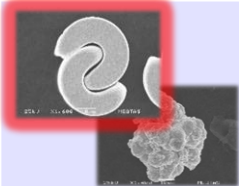
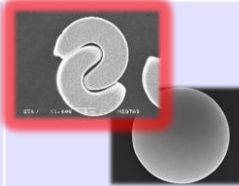
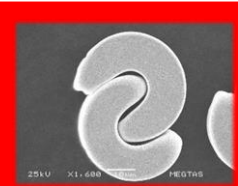
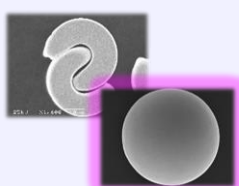

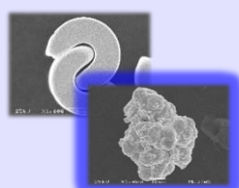
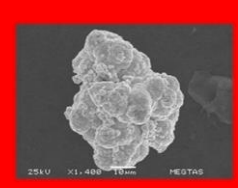
- Characteristic comparison for each particle shape

PARTICLE	HARDNESS	ADHESION with SILICONE	CONSISTENT CONTACT	COST
	O	O	O	X
	X	O	O	O
	O	X	O	O

<O : GOOD, X : BAD>

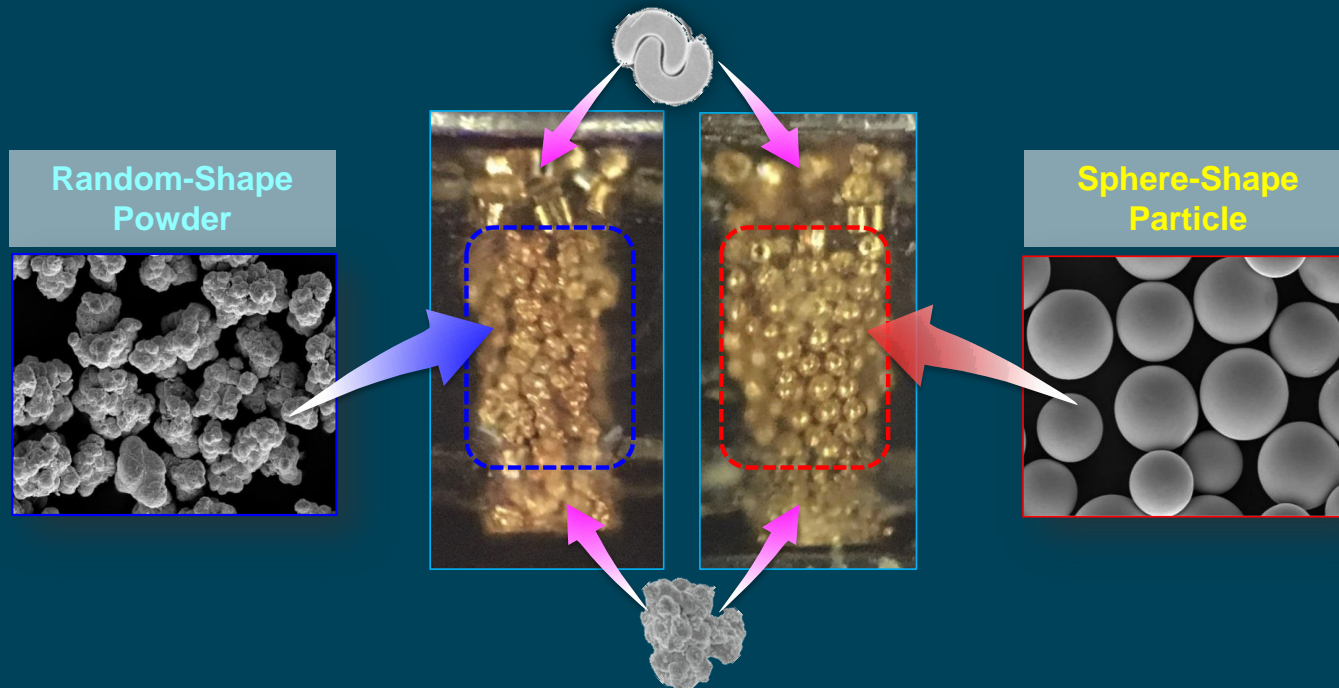
Investigation

- What is the requirement & best choice for each layers?

LAYERS	CONTACT OBJECT	HARDNESS	ADHESION with SILICONE	CONSISTENT CONTACT	BEST CHOICE
TOP	Ball				
BODY	Each Particle	N/A	N/A		
BOTTOM	PCB Gold Pad	N/A		N/A	

Investigation

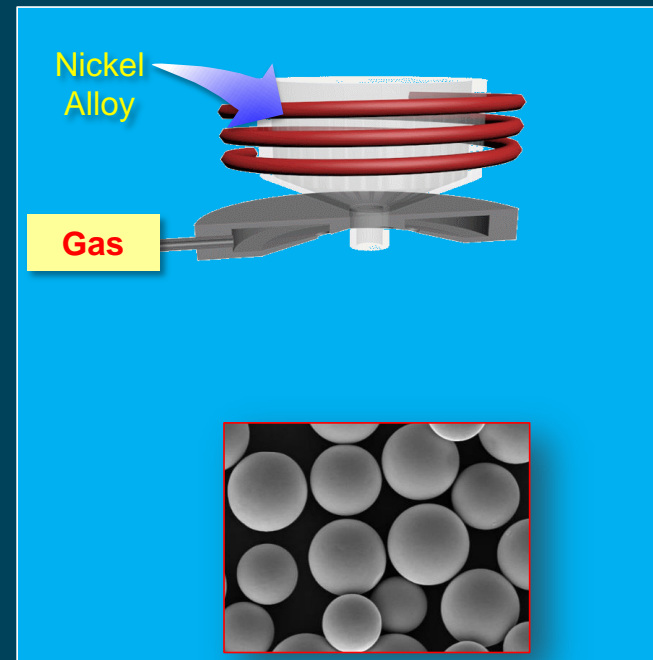
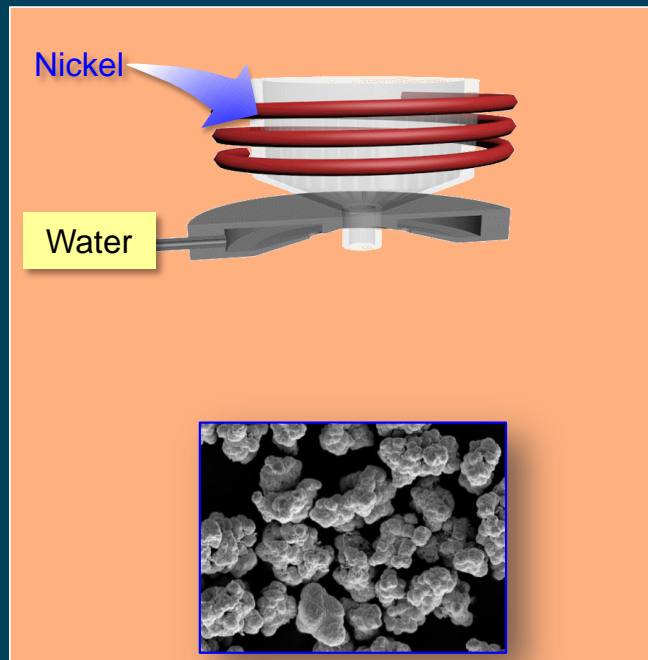
- How to improve contact durability of the Bump body?



- ✓ Do spherical-shaped particles increase elastomer socket lifecycle?
- ✓ Do spherical-shaped particles improved contact stability and repeatability?

Comparison

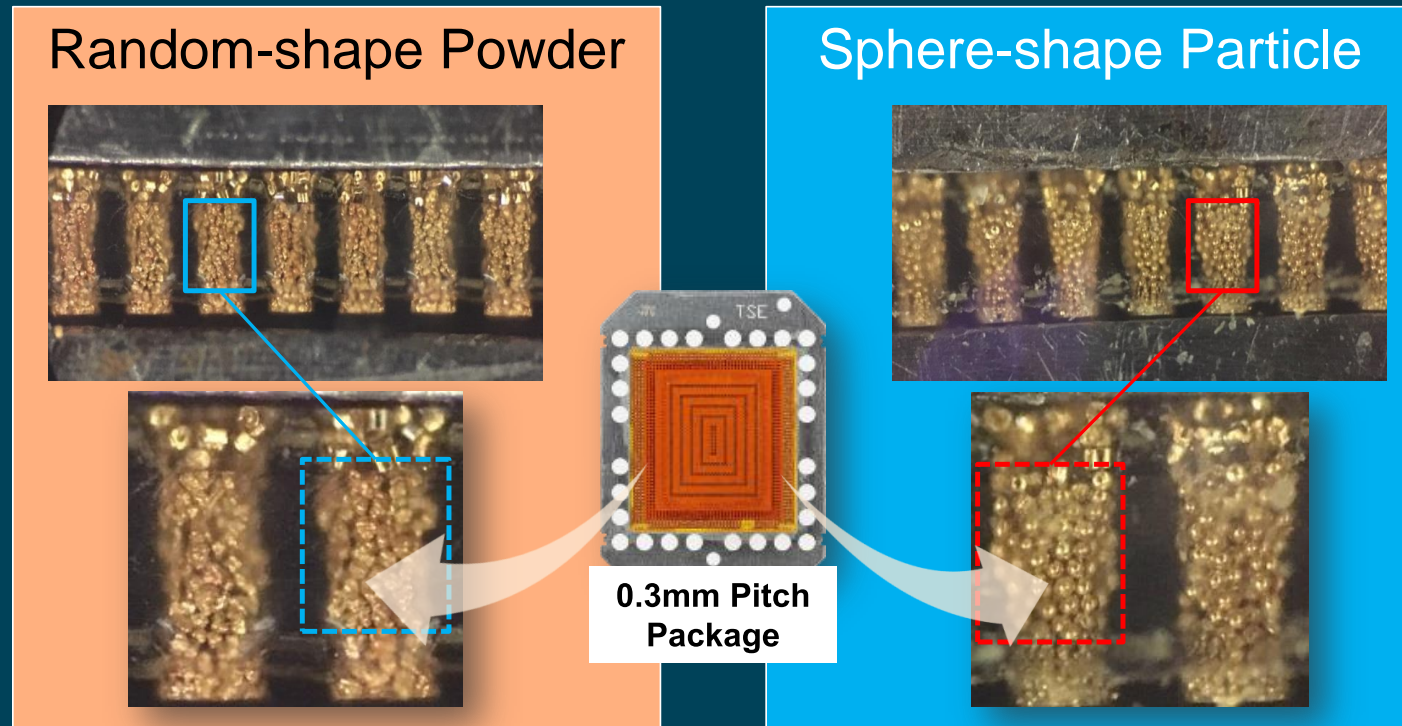
▪ Random-shape Powder vs. Sphere-shape Particle



- ✓ Random-shape powder is made by water atomization process.
- ✓ Sphere-shape particle is made by gas atomization process.

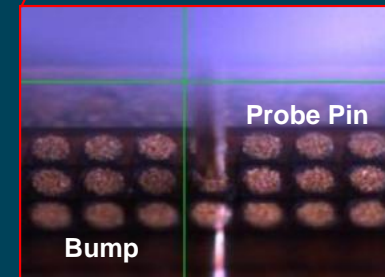
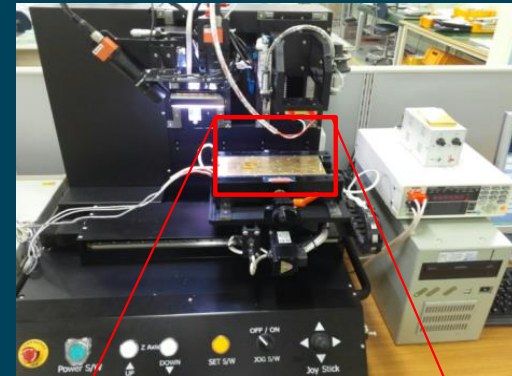
Test Sample

- Random-shape Powder vs. Sphere-shape Particle

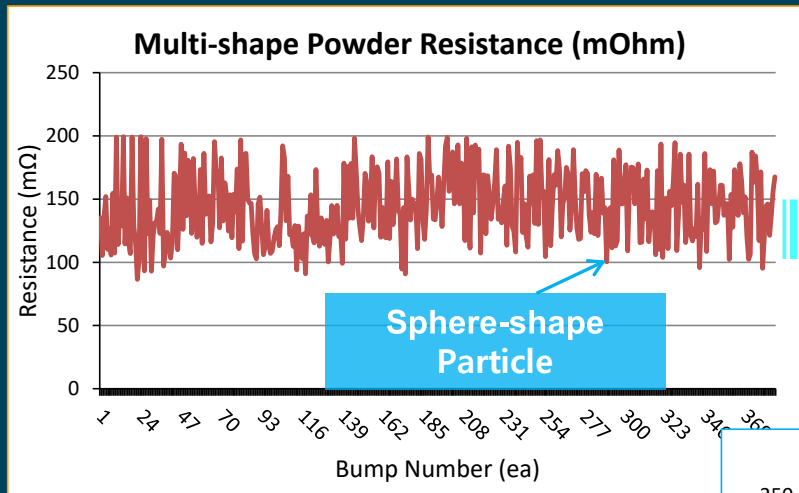


Evaluation

- **Resistance / Lifespan / Current Carrying Capacity**
 - ✓ Tester : TSE IT-490
 - ✓ Temp : 23°C
 - ✓ Probe Size : $\varnothing 0.19\text{mm}$
 - ✓ Probe Material : BeCu + Plating Au
 - ✓ Lifespan Stroke : 100 μm
 - ✓ Lifespan : Touch Down 300K
 - ✓ C.C.C Contact stroke : stroke @Force 10g
 - ✓ DC Power Supply 3306D (Max. 6A)

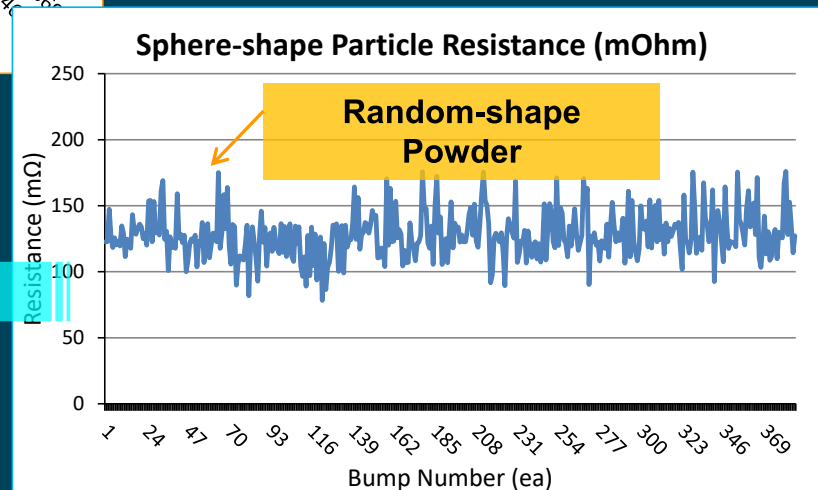


Evaluation – Resistance

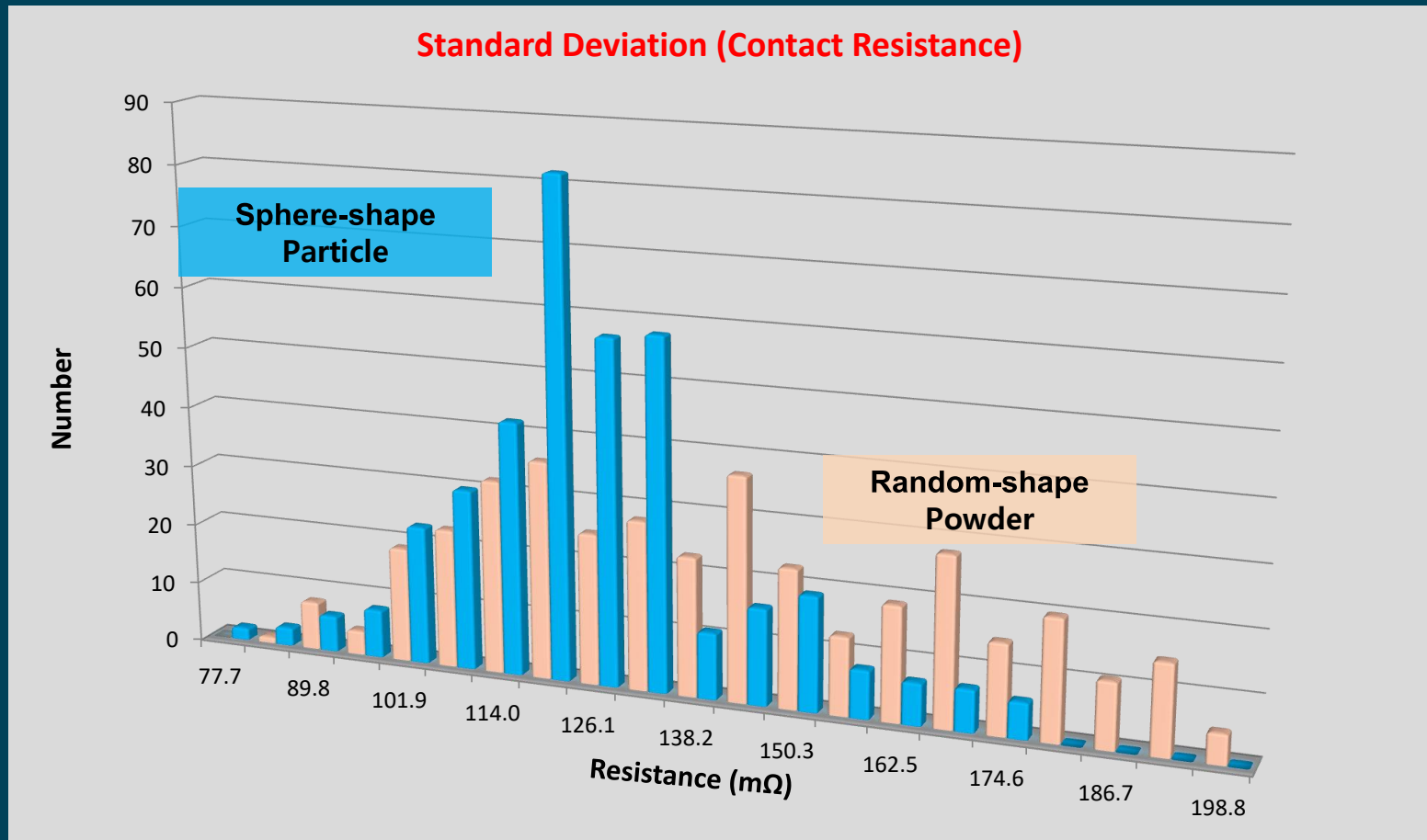


Resistance (mΩ)	
Minimum	86.5
Maximum	199.37
Average	144.15
Standard Deviation	27.7

Resistance (mΩ)	
Minimum	78.32
Maximum	175.95
Average	127.82
Standard Deviation	17.51

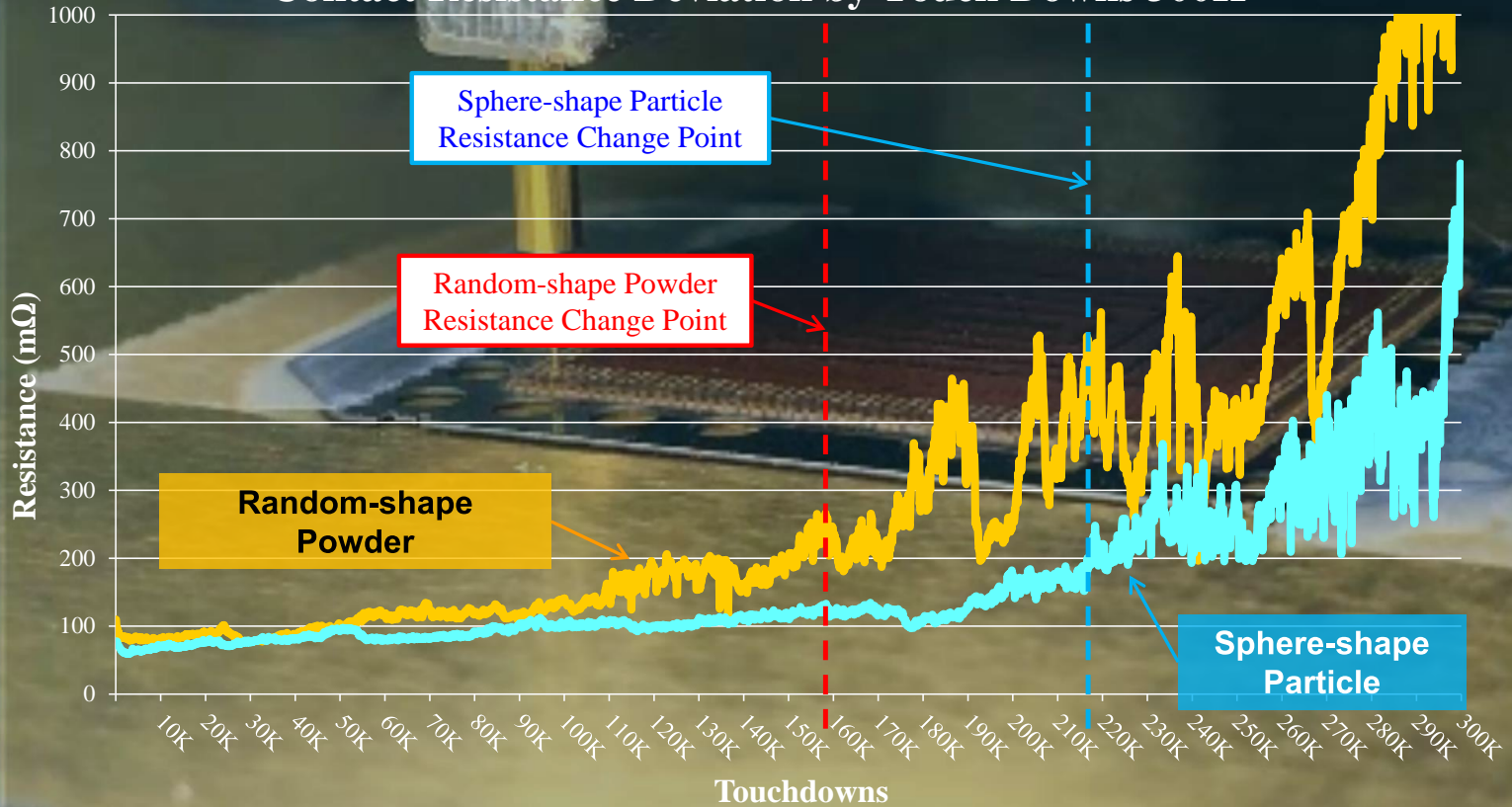


Evaluation – Resistance



Evaluation - Lifespan

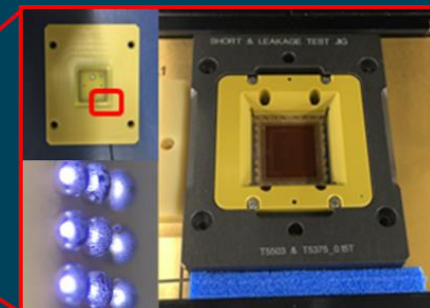
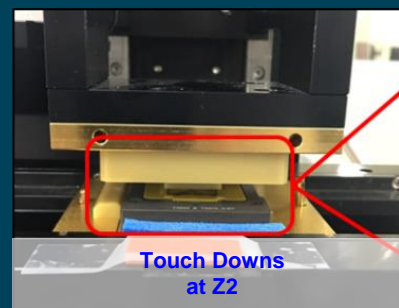
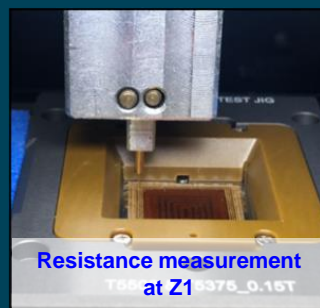
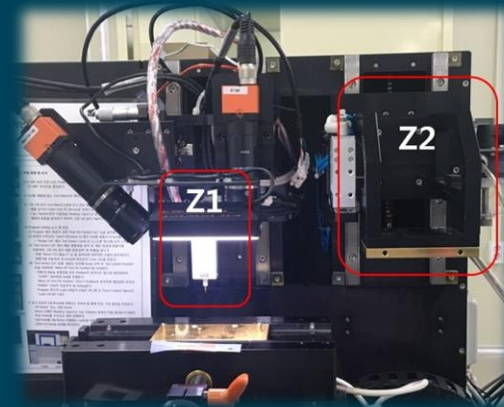
Contact Resistance Deviation by Touch Downs 300K



Evaluation – Lifespan (Whole Bump)

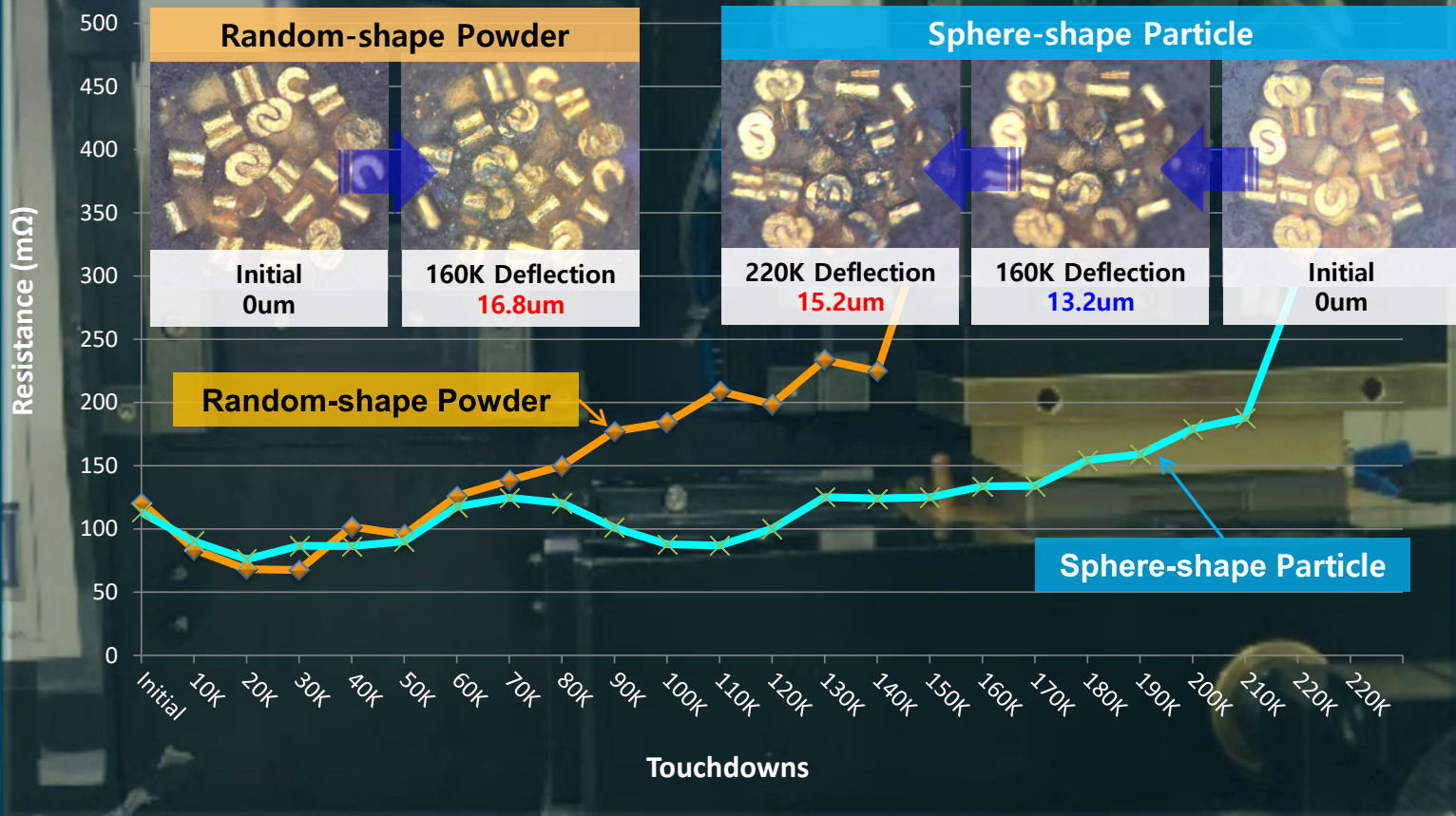
■ Lifespan Evaluation Condition

- ✓ Tester : TSE IT-490
- ✓ Temp : 23°C
- ✓ Dummy Device Ball Size : $\phi 0.23\text{mm}$
- ✓ Dummy Device Ball Material : (Pb Free) Sn
- ✓ Stroke : 100 μm
- ✓ Lifespan : Resistance Change Point
- ✓ Dummy Package was changed after every 10K touchdown.

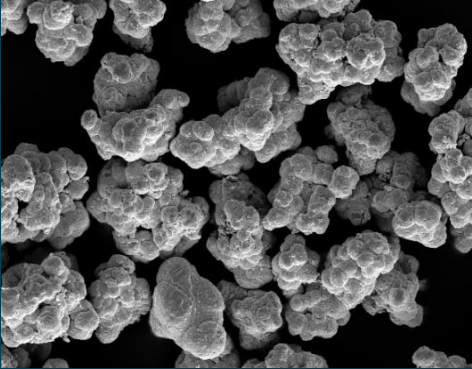
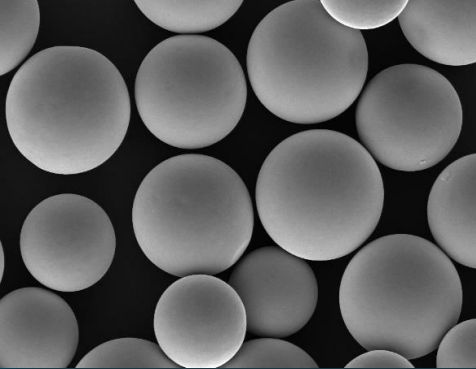


Evaluation – Lifespan (Whole Bump)

Average Contact Resistance Deviation by Touchdown



Evaluation – C.C.C

	Random-shape Powder	Sphere-shape Particle
		
Min.	1.42A	1.82A
Max.	2.49A	2.33A
Average	1.78A	1.95A
STD	0.39	0.19

Evaluation – Customer Production Site

■ Package Specification

- ✓ Time Controller 112BGA 0.65Pitch / Max Speed 3Gbps
- ✓ Facility : V93K – Handler (Seiko Epson NS7080)

■ Lifespan

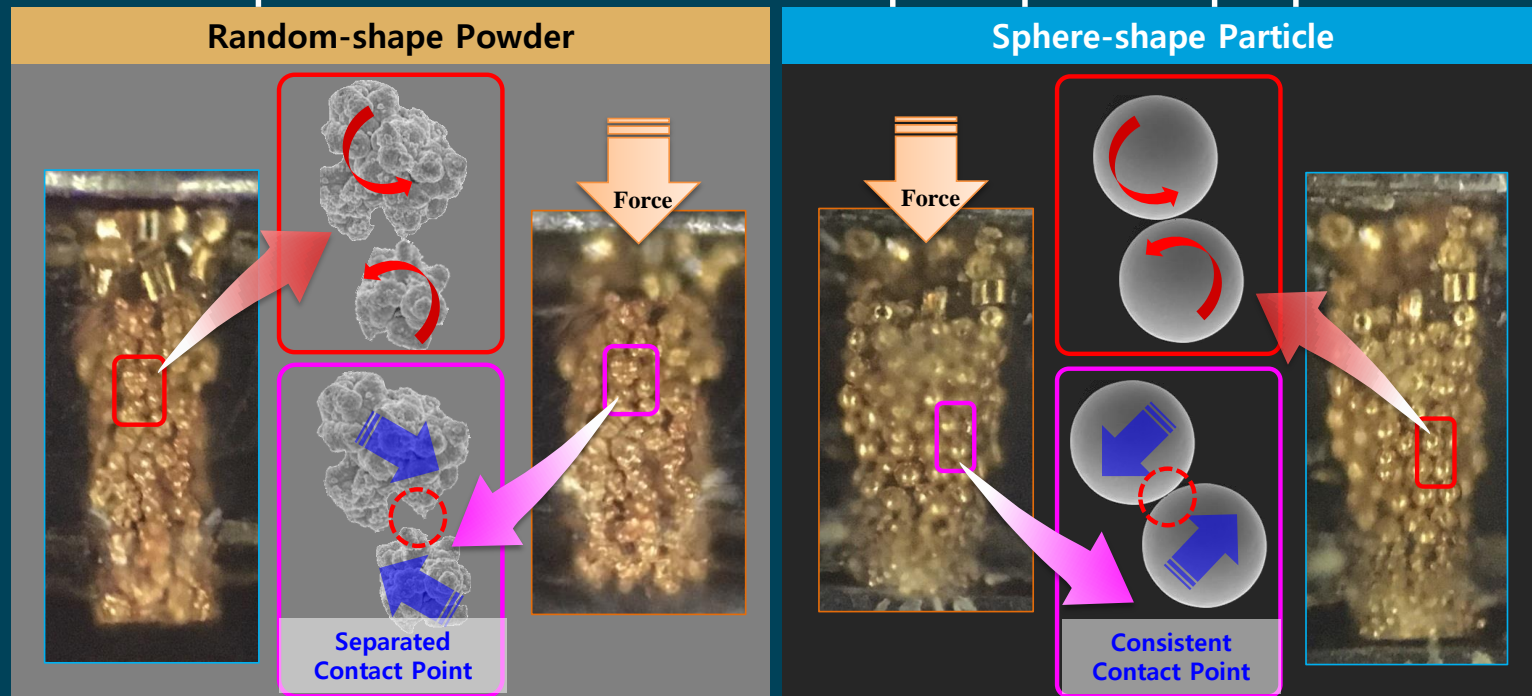
- ✓ Test Start Date June 10th, 2016
- ✓ Socket with Random-shape Powder : Test Ended after 78.5K Touch Down
- ✓ Socket with Sphere-shape Particle : 175.5K Tested since Oct. 14th
- ✓ Accumulated Average Yield was Increased 3~4% up to 78.5K

	SITE	IN QTY	OUT QTY	FAIL QTY	PASS RATE	OS QTY	OS RATE
Multi-shape Powder	S1	78531	67304	11227	85.704	198	0.253
	S2	78561	69319	9242	88.236	80	0.102
Sphere-shape Particle	S3	175500	164135	11365	93.524	56	0.032
	S4	175620	163349	12271	93.013	42	0.024

Analysis

Consistent Contact Point

- ✓ Elastomer & Powder are not damaged due to smooth particle surface & sliding contact motion
- ✓ Contact point is stable due to uniform shape of Sphere-shaped particles

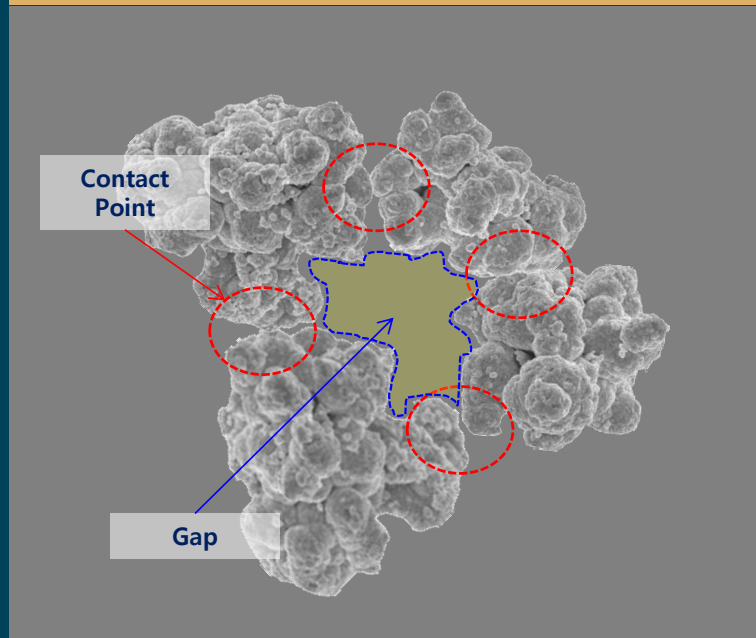


Analysis

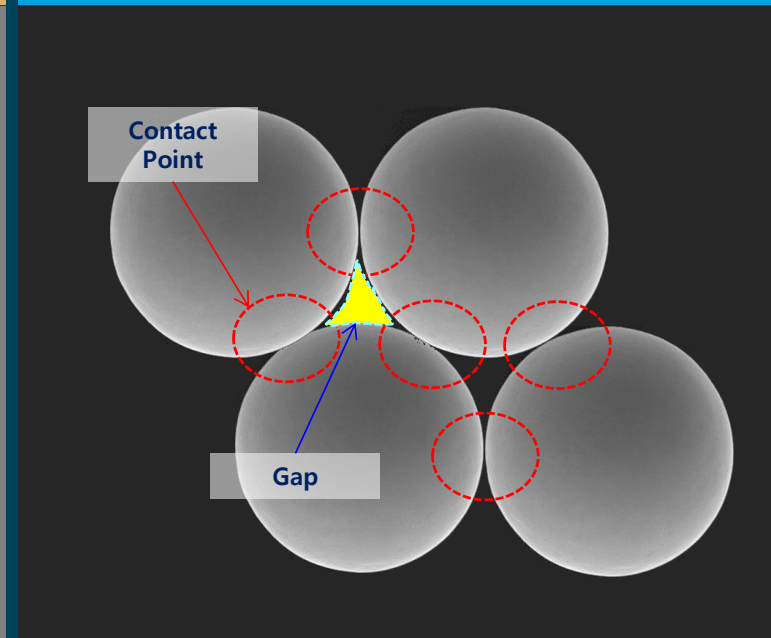
Continuous Contact Point

- ✓ S-shaped particles provide geometrically uniform distribution of contact force
- ✓ S-shaped particles minimize gaps and provide more consistent contact force

Random-shape Powder



Sphere-shape Particle



Summary

- **Short Term Resistance**
 - ✓ **Sphere-shape particles provide stable contact resistance compared to Random-shape powder**

- **Lifespan (Resistance Increase by Touchdown)**
 - ✓ **Sphere-shape particles improve bump body durability compared to Random-shape powder**

Summary

- **Deflection**

- ✓ **Sphere-shape particles reduces deflection compared to Random-shape powder**

- **C.C.C**

- ✓ **Sphere-shaped particles improve current capacity compared to Random-shape powder**

Conclusion

- **Particle Shape**
 - ✓ Particle conductivity is improved by altering the particle shape
- **Sphere-shape Particle**
 - ✓ Controlled sphere-shaped particles creates a repeatable and robust electromechanical contact
 - ✓ Utilization of Sphere-shape particles in the Bump Body prevents silicon damage and contact pressure concentration which improves the long-term mechanical performance of MRC sockets
 - Durability improved
 - Contact point stability improved
 - Deflection decreased